

FDP047N08 N-Channel PowerTrench[®] MOSFET 75V, 164A, 4.7m Ω

Features

- $R_{DS(on)} = 3.8 m\Omega$ (Typ.) @ $V_{GS} = 10V$, $I_D = 80A$
- Fast switching speed
- Low gate charge
- High performance trench technology for extremely low R_{DS(on)}
- High power and current handling capability
- RoHS compliant

Description

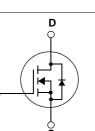
This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Application

• DC to DC convertors / Synchronous Rectification



TO-220



March 2008



Symbol		Parameter	Ratings	Units	
V _{DSS}	Drain to Source Voltage		75	V	
V _{GSS}	Gate to Source Voltage		±20	V	
I _D	Duala Quanant	-Continuous ($T_C = 25^{\circ}C$)		164*	А
	DrainCurrent	-Continuous ($T_c = 100^{\circ}C$)		116*	А
I _{DM}	DrainCurrent	- Pulsed (Note 1)		656	А
E _{AS}	Single Pulsed Avalanche Energy (Note 2)			670	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3		(Note 3)	3.0	V/ns
P _D	Devues Dissignation	$(T_{C} = 25^{\circ}C)$		268	W
	Power Dissipation	- Derate above 25°C		1.79	W/ºC
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +175	°C
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

*Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 80A.

Thermal Characteristics

Symbol	Parameter	Ratings	
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.56	
R _{0CS} Thermal Resistance, Case to Sink Typ.		0.5	
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	62.5	

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FDP047N08
N-Channel
PowerTrench [®]
MOSFET

Device Marking Device		Package	Package Reel Size Tape		e Width		Quantity			
FDP047N08 FDP047N08 TO-22			TO-220	20 -			- 50			
Electrica	l Char	acteristics								
Symbol		Parameter		T	est Conditions	6	Min.	Тур.	Max.	Units
Off Charac	teristic	S				·				
BV _{DSS}	Drain to	Source Breakdown V	/oltage	In = 250µA	$V_{CC} = 0V_{c}T_{C}$	= 25°C	75	-	-	V
∆BV _{DSS}		ain to Source Breakdown Voltage eakdown Voltage Temperature pefficient		$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}, T_C = 25^{\circ}\text{C}$ $I_D = 250\mu\text{A}, \text{Referenced to } 25^{\circ}\text{C}$			10			-
$/ \Delta T_J$							-	0.02	-	V/°C
 	Zero Gate Voltage Drain Current			$V_{DS} = 75V, V_{GS} = 0V$ $V_{DS} = 75V, T_{C} = 150^{\circ}C$			-	-	1	
DSS							-	-	500	μA
I _{GSS}	Gate to	Gate to Body Leakage Current			V, V _{DS} = 0V		-	-	±100	nA
On Charac	teristic	S								
V _{GS(th)}	Gate Th	nreshold Voltage		$V_{GS} = V_{DS}, I_{D} = 250 \mu A$			2.5	3.5	4.5	V
R _{DS(on)}		rain to Source On Res		$V_{GS} = 10V, I_D = 80A$			-	3.7	4.7	mΩ
9 _{FS}	Forward Transconductance			V _{DS} = 10V	-	(Note 4)	-	150	-	S
Dynamic C	Characte	eristics								
C _{iss}	Input Capacitance				-	7080	9415	pF		
C _{oss}		t Capacitance		$V_{DS} = 25V, V_{GS} = 0V$			-	870	1155	pF
C _{rss}		e Transfer Capacitance		f = 1MHz			-	410	615	pF
Switching	Charac	toristics	I	I						. ·
-								100	210	ns
t _{d(on)}		urn-On Delay Time urn-On Rise Time		$V_{DD} = 37.5V, I_D = 80A$ $R_{GEN} = 25\Omega, V_{GS} = 10V$ (Note 4, 5)			-	100	304	ns
t _r								220	450	ns
t _{d(off)}		urn-Off Delay Time urn-Off Fall Time					_	114	238	ns
t _f		ate Charge at 10V				(NOLE 4, 5)	-	114	152	nC
Q _{g(tot)}		Source Gate Charge		$V_{DS} = 60V, I_{D} = 80A$		-	-	37	152	nC
Q _{gs}		-		$V_{GS} = 10V$			-	-	-	-
Q _{gd}	Gate to	Gate to Drain "Miller" Charge			(Note 4, 5)			32	-	nC
Drain-Sou	rce Diod	de Characteristic	s							
I _S	Maximum Continuous Drain to Source Diod				urrent		-	-	164	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Fo			orward Current			-	-	656	Α
V _{SD}	Drain to Source Diode Forward Voltage			V _{GS} = 0V, I _{SD} = 80A			-	-	1.25	V
t _{rr}	Reverse	Recovery Time		$V_{GS} = 0V, I_{SD} = 80A$		-	45	-	ns	
Q _{rr}	Reverse	e Recovery Charge		$dI_F/dt = 10$		(Note 4)	-	66	-	nC
2. L = 0.21mH, I _{AS}	= 80A, V _{DD} =	h limited by maximum junction = 50V, $R_G = 25\Omega$, Starting $T_J = 25^{\circ} \leq BV_{DSS}$, Starting $T_J = 25^{\circ}$	= 25°C							

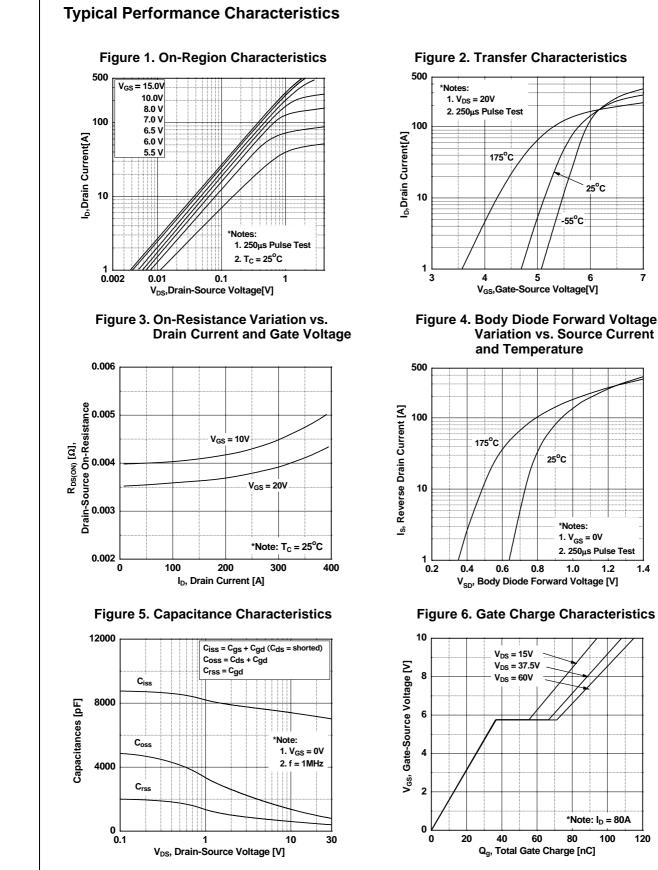


Figure 2. Transfer Characteristics

Variation vs. Source Current and Temperature

5

25°C

6

7

-55°C

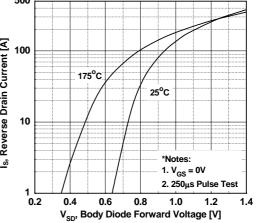
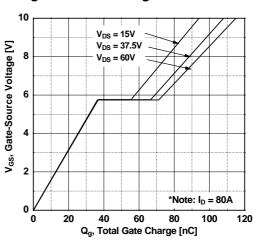
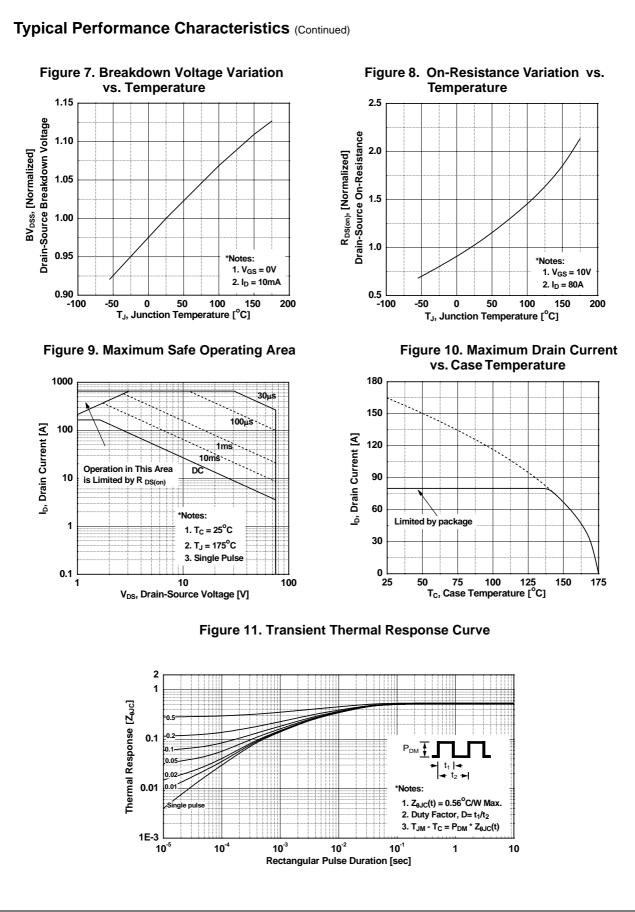
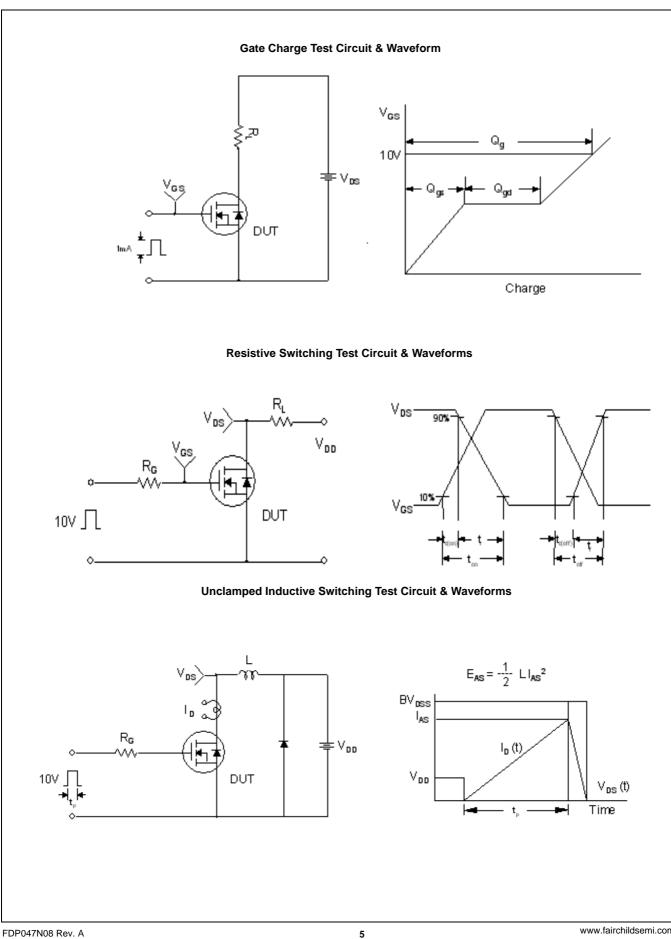


Figure 6. Gate Charge Characteristics



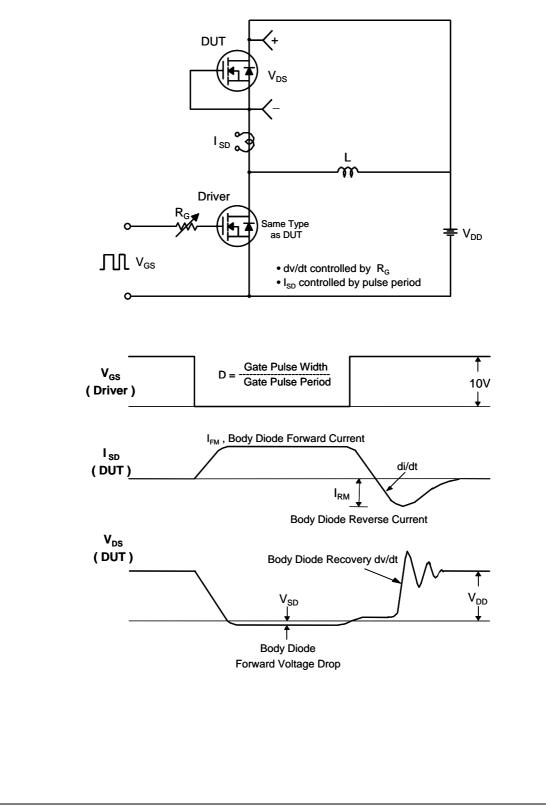


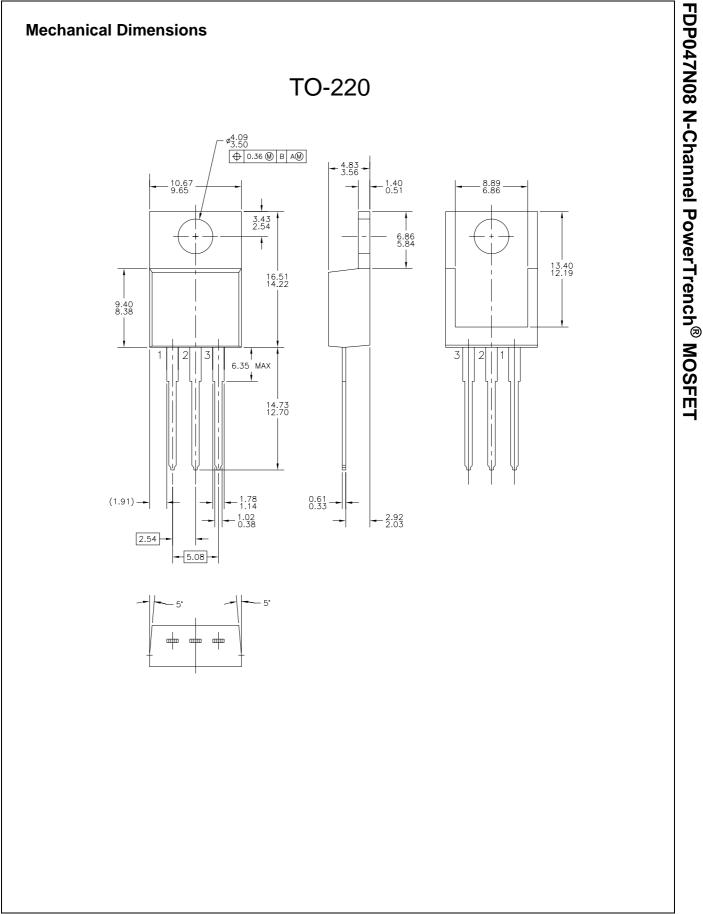
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7



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